



CY7C199

32K x 8 Static RAM

Features

- High speed
 - 10 ns
- Fast t_{DOE}
- CMOS for optimum speed/power
- Low active power
 - 467 mW (max, 12 ns "L" version)
- Low standby power
 - 0.275 mW (max, "L" version)
- 2V data retention ("L" version only)
- Easy memory expansion with \overline{CE} and \overline{OE} features
- TTL-compatible inputs and outputs
- Automatic power-down when deselected

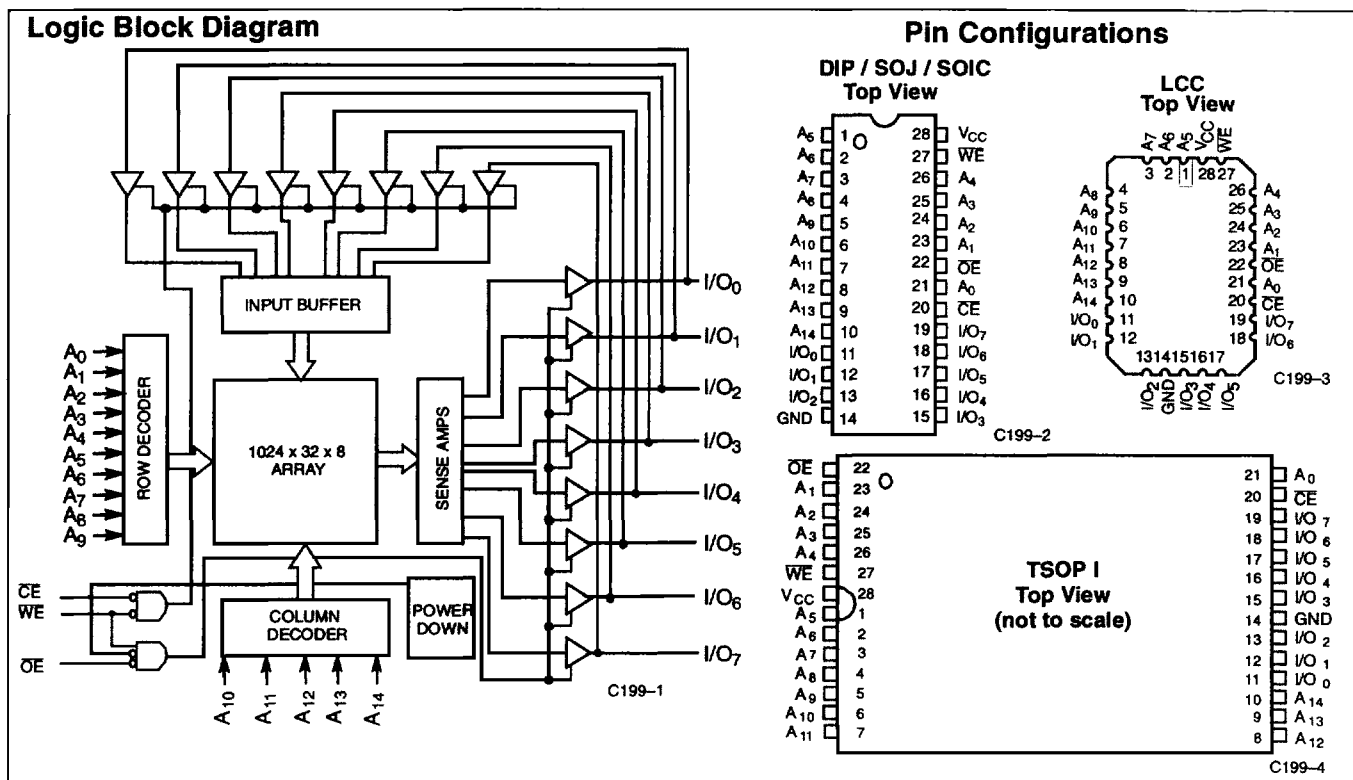
provided by an active LOW chip enable (\overline{CE}) and active LOW output enable (\overline{OE}) and three-state drivers. This device has an automatic power-down feature, reducing the power consumption by 81% when deselected. The CY7C199 is in the standard 300-mil-wide DIP, SOJ, and LCC packages.

An active LOW write enable signal (\overline{WE}) controls the writing/reading operation of the memory. When \overline{CE} and \overline{WE} inputs are both LOW, data on the eight data input/output pins (I/O_0 through I/O_7) is written into the memory location addressed by the address present on the address pins (A_0 through A_{14}). Reading the device is accomplished by selecting the device and enabling the outputs, \overline{CE} and \overline{OE} active LOW, while \overline{WE} remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and write enable (\overline{WE}) is HIGH. A die coat is used to improve alpha immunity.

Functional Description

The CY7C199 is a high-performance CMOS static RAM organized as 32,768 words by 8 bits. Easy memory expansion is



Selection Guide

	7C199-8	7C199-10	7C199-12	7C199-15	7C199-20	7C199-25	7C199-35	7C199-45
Maximum Access Time (ns)	8	10	12	15	20	25	35	45
Maximum Operating Current (mA)		120	110	160	150	150	140	140
	L	85	85	100	90	80	70	
Maximum CMOS Standby Current (mA)		0.5	0.5	10	10	10	10	10
	L	0.05	0.05	0.05	0.05	0.05	0.05	

CYP RS285



Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

- Storage Temperature -65°C to +150°C
- Ambient Temperature with Power Applied..... -55°C to +125°C
- Supply Voltage to Ground Potential (Pin 28 to Pin 14)..... -0.5V to +7.0V
- DC Voltage Applied to Outputs in High Z State^[1]..... -0.5V to V_{CC} + 0.5V
- DC Input Voltage^[1]..... -0.5V to V_{CC} + 0.5V

- Output Current into Outputs (LOW)..... 20 mA
- Static Discharge Voltage >2001V (per MIL-STD-883, Method 3015)
- Latch-Up Current..... >200 mA

Operating Range

Range	Ambient Temperature ^[2]	V _{CC}
Commercial	0°C to +70°C	5V ± 10%
Industrial	-40°C to +85°C	5V ± 10%
Military	-55°C to +125°C	5V ± 10%

Electrical Characteristics Over the Operating Range^[3]

Parameter	Description	Test Conditions	7C199-8		7C199-10		7C199-12		7C199-15		Unit	
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
V _{OH}	Output HIGH Voltage	V _{CC} =Min., I _{OH} =-4.0 mA	2.4		2.4		2.4		2.4		V	
V _{OL}	Output LOW Voltage	V _{CC} =Min., I _{OL} =8.0 mA		0.4		0.4		0.4		0.4	V	
V _{IH}	Input HIGH Voltage		2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	V	
V _{IL}	Input LOW Voltage		-0.5	0.8	-0.5	0.8	-0.5	0.8	-0.5	0.8	V	
I _{IX}	Input Load Current	GND ≤ V _I ≤ V _{CC}	-5	+5	-5	+5	-5	+5	-5	+5	µA	
I _{OZ}	Output Leakage Current	GND ≤ V _O ≤ V _{CC} , Output Disabled	-5	+5	-5	+5	-5	+5	-5	+5	µA	
I _{CC}	V _{CC} Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX} = 1/t _{RC}	Com'l	120		110		160		155	mA	
			L			85		85		100	mA	
			Mil							180	mA	
I _{SB1}	Automatic CE Power-Down Current— TTL Inputs	Max. V _{CC} , CE ≥ V _{IH} , V _{IN} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f = f _{MAX}	Com'l	5		5		30		30	mA	
			L			5		5		5	mA	
I _{SB2}	Automatic CE Power-Down Current— CMOS Inputs	Max. V _{CC} , CE ≥ V _{CC} - 0.3V, V _{IN} ≥ V _{CC} - 0.3V or V _{IN} ≤ 0.3V, f = 0	Com'l	0.5		0.5		10		10	mA	
			L		0.05		0.05		0.05		0.05	mA
			Mil							15	mA	

Notes:

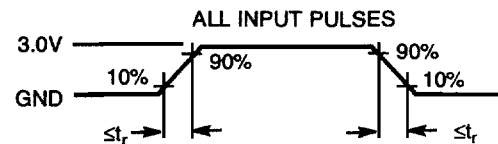
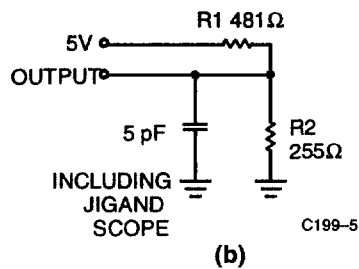
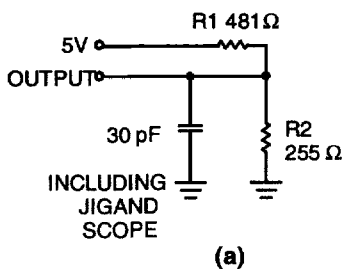
1. V_{IL} (min.) = -2.0V for pulse durations of less than 20 ns.
2. T_A is the "instant on" case temperature.
3. See the last page of this specification for Group A subgroup testing information.

Electrical Characteristics Over the Operating Range^[3] (continued)

Parameter	Description	Test Conditions	7C199-20		7C199-25		7C199-35		7C199-45		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
V _{OH}	Output HIGH Voltage	V _{CC} =Min., I _{OH} =-4.0 mA	2.4		2.4		2.4		2.4		V
V _{OL}	Output LOW Voltage	V _{CC} =Min., I _{OL} =8.0 mA		0.4		0.4		0.4		0.4	V
V _{IH}	Input HIGH Voltage		2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	2.2	V _{CC} +0.3V	V
V _{IL}	Input LOW Voltage		-0.5	0.8	-3.0	0.8	-3.0	0.8	-3.0	0.8	V
I _{IX}	Input Load Current	GND ≤ V _I ≤ V _{CC}	-5	+5	-5	+5	-5	+5	-5	+5	μA
I _{OZ}	Output Leakage Current	GND ≤ V _I ≤ V _{CC} , Output Disabled	-5	+5	-5	+5	-5	+5	-5	+5	μA
I _{CC}	V _{CC} Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX} = 1/t _{RC}	Com'l	150		150		140		140	mA
			L	90		80		70		70	mA
			Mil	170		150		150		150	mA
I _{SB1}	Automatic CE Power-Down Current—TTL Inputs	Max. V _{CC} , CE ≥ V _{IH} , V _{IN} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f = f _{MAX}	Com'l	30		30		25		25	mA
			L	5		5		5		5	mA
I _{SB2}	Automatic CE Power-Down Current—CMOS Inputs	Max. V _{CC} , CE ≥ V _{CC} - 0.3V V _{IN} ≥ V _{CC} - 0.3V or V _{IN} ≤ 0.3V, f=0	Com'l	10		10		10		10	mA
			L	0.05		0.05		0.05		0.05	μA
			Mil	15		15		15		15	mA

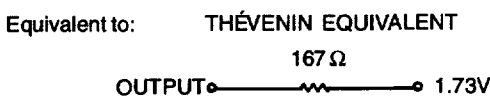
Capacitance^[4]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	T _A = 25°C, f = 1 MHz, V _{CC} = 5.0V	8	pF
C _{OUT}	Output Capacitance		8	pF

AC Test Loads and Waveforms^[5]


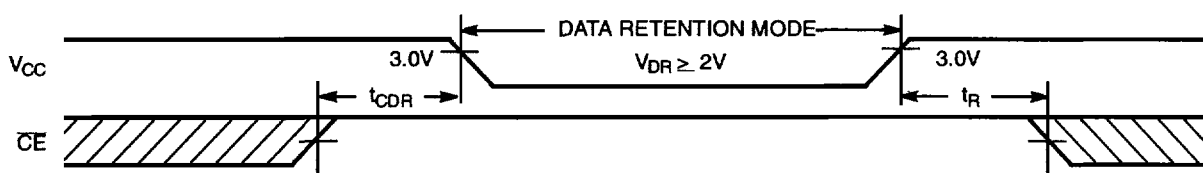
C199-5

C199-6



Data Retention Characteristics Over the Operating Range (L version only)

Parameter	Description	Conditions ^[6]	Min.	Max.	Unit
V_{DR}	V_{CC} for Data Retention		2.0		V
I_{CCDR}	Data Retention Current	Com'1			μA
		Com'1 L		10	μA
$t_{CDR}^{[4]}$	Chip Deselect to Data Retention Time	$V_{CC} = V_{DR} = 2.0V,$ $CE \geq V_{CC} - 0.3V,$ $V_{IN} \geq V_{CC} - 0.3V$ or $V_{IN} \leq 0.3V$	0		ns
$t_R^{[5]}$	Operation Recovery Time		t_{RC}		ns

Data Retention Waveform


C199-7

Notes:

4. Tested initially and after any design or process changes that may affect these parameters.
5. $t_R \leq 3$ ns for the -12 and -15 speeds. $t_R \leq 5$ ns for the -20 and slower speeds.
6. No input may exceed $V_{CC} + 0.5V$.



Switching Characteristics Over the Operating Range^[3, 7]

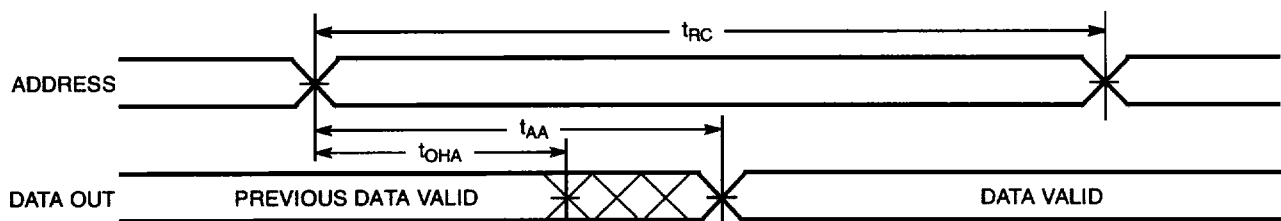
Parameter	Description	7C199-8		7C199-10		7C199-12		7C199-15		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE										
t _{RC}	Read Cycle Time	8		10		12		15		ns
t _{AA}	Address to Data Valid		8		10		12		15	ns
t _{OHA}	Data Hold from Address Change	3		3		3		3		ns
t _{ACE}	\overline{CE} LOW to Data Valid		8		10		12		15	ns
t _{DOE}	\overline{OE} LOW to Data Valid		4.5		5		5		7	ns
t _{LZOE}	\overline{OE} LOW to Low Z ^[8]	0		0		0		0		ns
t _{HZOE}	\overline{OE} HIGH to High Z ^[8, 9]		5		5		5		7	ns
t _{LZCE}	\overline{CE} LOW to Low Z ^[8]	3		3		3		3		ns
t _{HZCE}	\overline{CE} HIGH to High Z ^[8, 9]		4		5		5		7	ns
t _{PU}	\overline{CE} LOW to Power-Up	0		0		0		0		ns
t _{PD}	\overline{CE} HIGH to Power-Down		8		10		12		15	ns
WRITE CYCLE^[10, 11]										
t _{WC}	Write Cycle Time	8		10		12		15		ns
t _{SCE}	\overline{CE} LOW to Write End	7		7		9		10		ns
t _{AW}	Address Set-Up to Write End	7		7		9		10		ns
t _{HA}	Address Hold from Write End	0		0		0		0		ns
t _{SA}	Address Set-Up to Write Start	0		0		0		0		ns
t _{PWE}	\overline{WE} Pulse Width	7		7		8		9		ns
t _{SD}	Data Set-Up to Write End	5		5		8		9		ns
t _{HD}	Data Hold from Write End	0		0		0		0		ns
t _{HZWE}	\overline{WE} LOW to High Z ^[9]		5		6		7		7	ns
t _{LZWE}	\overline{WE} HIGH to Low Z ^[8]	3		3		3		3		ns

Notes:

- Test conditions assume signal transition time of 3 ns or less for -12 and -15 speeds and 5 ns or less for -20 and slower speeds, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
- At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any given device.
- t_{HZOE}, t_{HZCE}, and t_{HZWE} are specified with C_L = 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
- The internal write time of the memory is defined by the overlap of \overline{CE} LOW and \overline{WE} LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
- The minimum write cycle time for write cycle #3 (\overline{WE} controlled, \overline{OE} LOW) is the sum of t_{HZWE} and t_{SD}.

Switching Characteristics Over the Operating Range^[9,7] (continued)

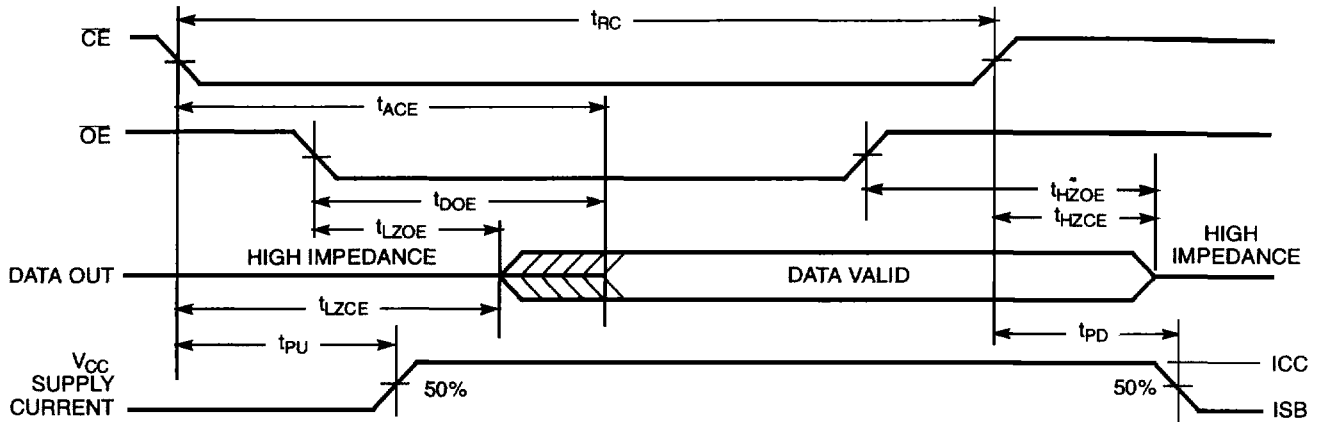
Parameter	Description	7C199-20		7C199-25		7C199-35		7C199-45		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
READ CYCLE										
t_{RC}	Read Cycle Time	20		25		35		45		ns
t_{AA}	Address to Data Valid		20		25		35		45	ns
t_{OHA}	Data Hold from Address Change	3		3		3		3		ns
t_{ACE}	\overline{CE} LOW to Data Valid		20		25		35		45	ns
t_{DOE}	\overline{OE} LOW to Data Valid		9		10		16		16	ns
t_{LZOE}	\overline{OE} LOW to Low $Z^{[8]}$	0		3		3		3		ns
t_{HZOE}	\overline{OE} HIGH to High $Z^{[8,9]}$		9		11		15		15	ns
t_{LZCE}	\overline{CE} LOW to Low $Z^{[8]}$	3		3		3		3		ns
t_{HZCE}	\overline{CE} HIGH to High $Z^{[8,9]}$		9		11		15		15	ns
t_{PU}	\overline{CE} LOW to Power-Up	0		0		0		0		ns
t_{PD}	\overline{CE} HIGH to Power-Down		20		20		20		25	ns
WRITE CYCLE^[10,11]										
t_{WC}	Write Cycle Time	20		25		35		45		ns
t_{SCE}	\overline{CE} LOW to Write End	15		18		22		22		ns
t_{AW}	Address Set-Up to Write End	15		20		30		40		ns
t_{HA}	Address Hold from Write End	0		0		0		0		ns
t_{SA}	Address Set-Up to Write Start	0		0		0		0		ns
t_{PWE}	\overline{WE} Pulse Width	15		18		22		22		ns
t_{SD}	Data Set-Up to Write End	10		10		15		15		ns
t_{HD}	Data Hold from Write End	0		0		0		0		ns
t_{HZWE}	\overline{WE} LOW to High $Z^{[9]}$		10		11		15		15	ns
t_{LZWE}	\overline{WE} HIGH to Low $Z^{[8]}$	3		3		3		3		ns

Switching Waveforms
Read Cycle No. 1^[12, 13]


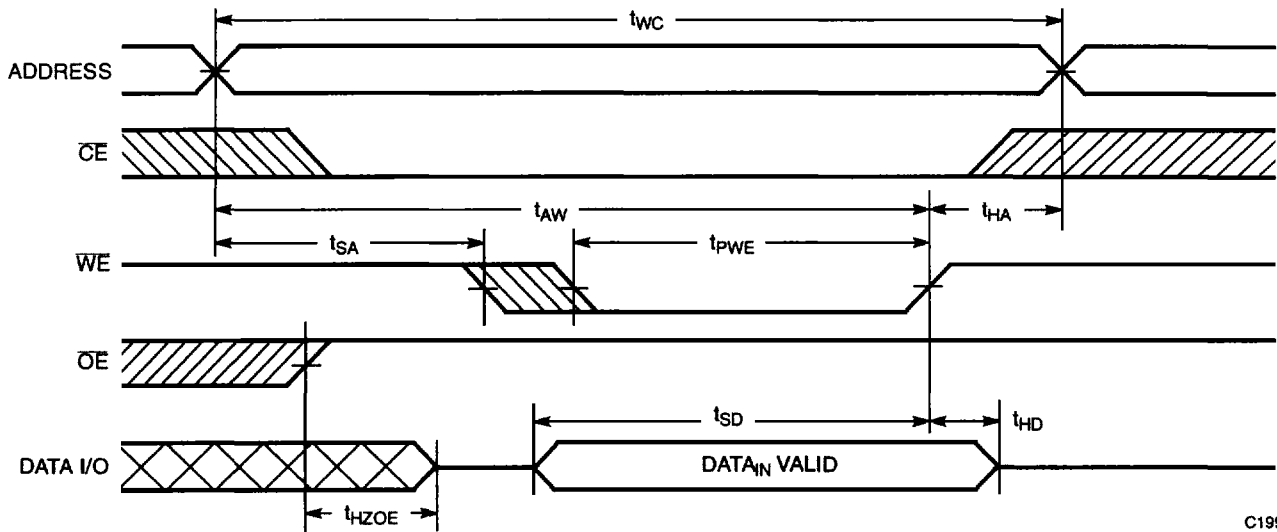
C199-8

Notes:

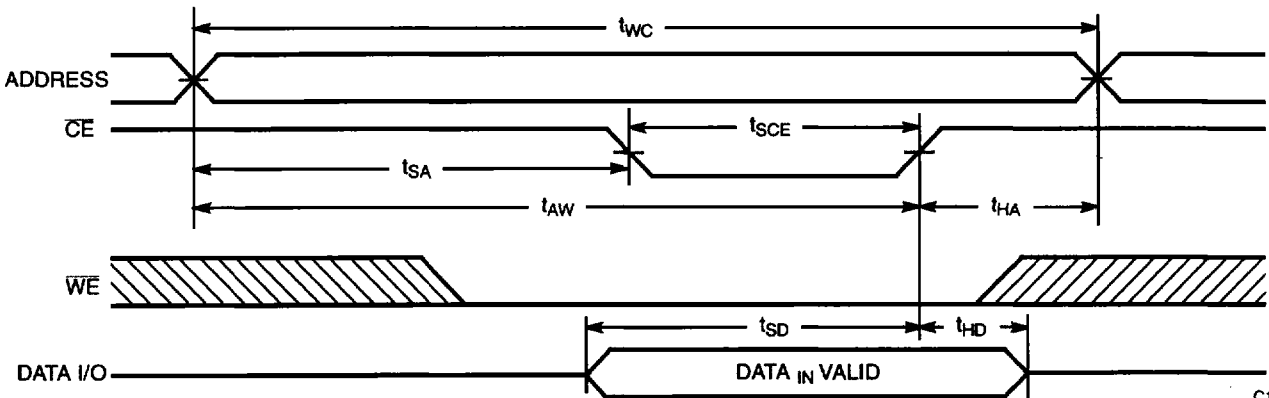
12. Device is continuously selected. \overline{OE} , $\overline{CE} = V_L$.
 13. \overline{WE} is HIGH for read cycle.

Switching Waveforms (continued)
Read Cycle No. 2 ^[13, 14]


C199-9

Write Cycle No. 1 (WE Controlled) ^[10, 15, 16]


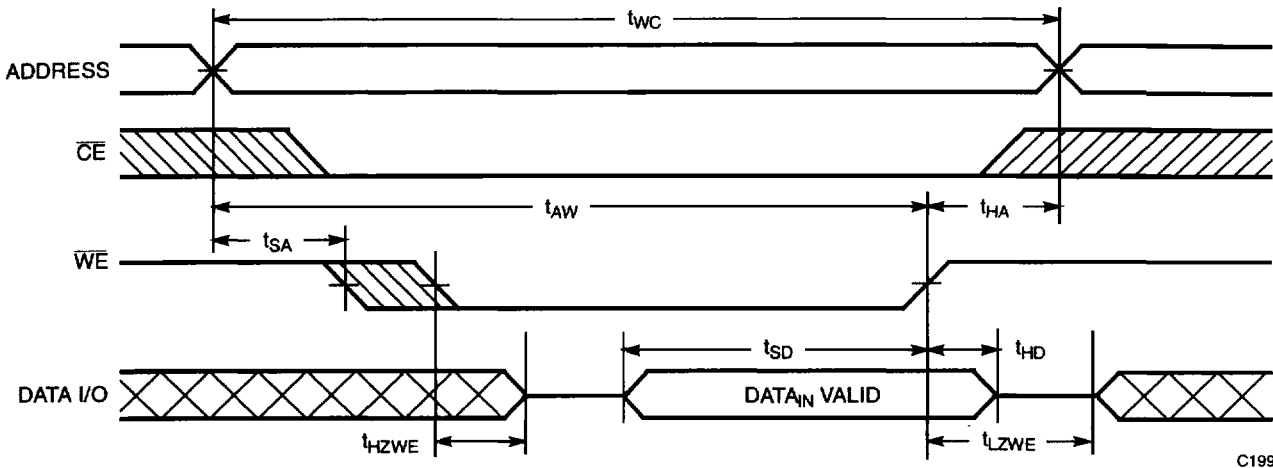
C199-10

Write Cycle No. 2 (CE Controlled) ^[10, 15, 16]


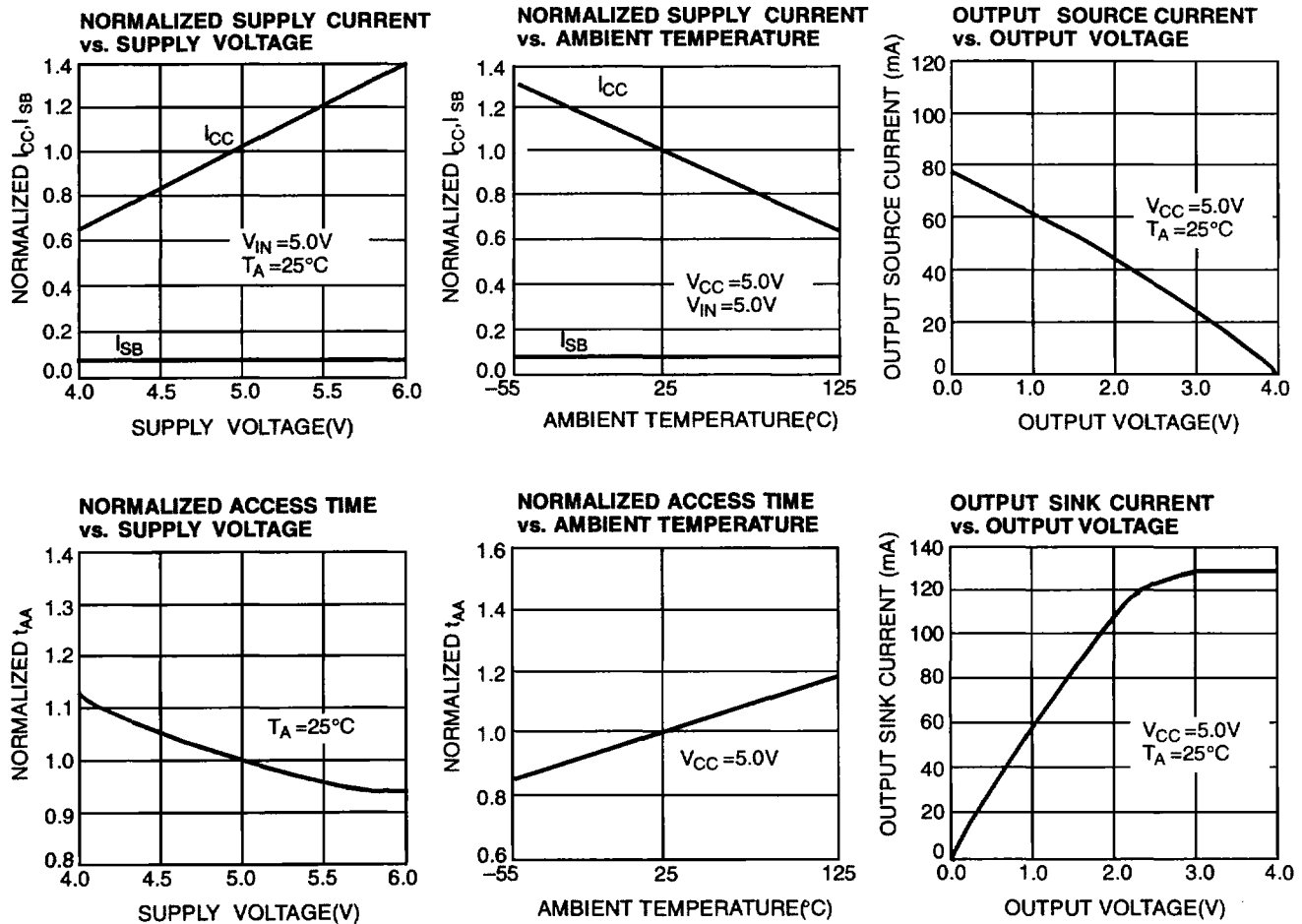
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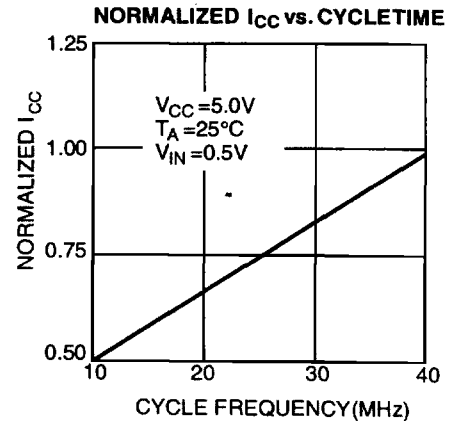
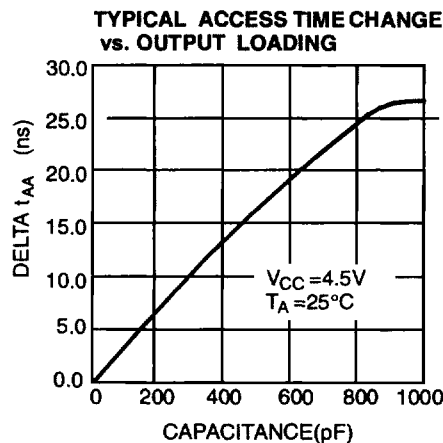
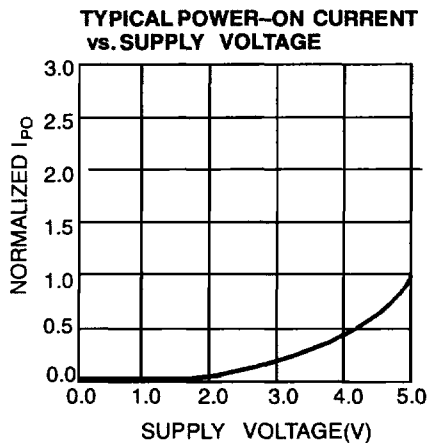
Notes:

14. Address valid prior to or coincident with CE transition LOW.
15. Data I/O is high impedance if $OE = V_{IH}$.
16. If CE goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.

Switching Waveforms (continued)
Write Cycle No. 3 (WE Controlled \overline{OE} LOW)^[11, 16]


C199-12

Typical DC and AC Characteristics


Typical DC and AC Characteristics (continued)

Truth Table

\overline{CE}	\overline{WE}	\overline{OE}	Inputs/Outputs	Mode	Power
H	X	X	High Z	Deselect/Power-Down	Standby (I_{SB})
L	H	L	Data Out	Read	Active (I_{CC})
L	L	X	Data In	Write	Active (I_{CC})
L	H	H	High Z	Deselect, Output Disabled	Active (I_{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
8	CY7C199-8VC	V21	28-Lead Molded SOJ	Commercial
	CY7C199-8ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-8VC	V21	28-Lead Molded SOJ	
	CY7C199L-8ZC	Z28	28-Lead Thin Small Outline Package	
10	CY7C199-10VC	V21	28-Lead Molded SOJ	Commercial
	CY7C199-10ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-10VC	V21	28-Lead Molded SOJ	
	CY7C199L-10ZC	Z28	28-Lead Thin Small Outline Package	
	Industrial	CY7C199-10VI	V21	28-Lead Molded SOJ
		CY7C199-10ZI	Z28	28-Lead Thin Small Outline Package
		CY7C199L-10VI	V21	28-Lead Molded SOJ
		CY7C199L-10ZI	Z28	28-Lead Thin Small Outline Package
12	CY7C199-12PC	P21	28-Lead (300Mil) Molded DIP	Commercial
	CY7C199-12VC	V21	28-Lead Molded SOJ	
	CY7C199-12ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-12PC	P21	28-Lead (300Mil) Molded DIP	
	CY7C199L-12VC	V21	28-Lead Molded SOJ	
	CY7C199L-12ZC	Z28	28-Lead Thin Small Outline Package	
	Industrial	CY7C199-12VI	V21	28-Lead Molded SOJ
		CY7C199-12ZI	Z28	28-Lead Thin Small Outline Package
		CY7C199L-12VI	V21	28-Lead Molded SOJ
		CY7C199L-12ZI	Z28	28-Lead Thin Small Outline Package



Ordering Information (continued)

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C199-15PC	P21	28-Lead (300Mil) Molded DIP	Commercial
	CY7C199-15VC	V21	28-Lead Molded SOJ	
	CY7C199-15ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-15PC	P21	28-Lead (300Mil) Molded DIP	
	CY7C199L-15VC	V21	28-Lead Molded SOJ	
	CY7C199L-15ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199-15VI	V21	28-Lead Molded SOJ	Industrial
	CY7C199-15ZI	Z28	28-Lead Thin Small Outline Package	Military
	CY7C199-15DMB	D22	28-Lead (300Mil) CerDIP	
	CY7C199-15LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
	CY7C199L-15DMB	D22	28-Lead (300Mil) CerDIP	
	CY7C199L-15LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
20	CY7C199-20PC	P21	28-Lead (300Mil) Molded DIP	Commercial
	CY7C199-20VC	V21	28-Lead Molded SOJ	
	CY7C199-20ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-20PC	P21	28-Lead (300Mil) Molded DIP	
	CY7C199L-20VC	V21	28-Lead Molded SOJ	
	CY7C199L-20ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199-20VI	V21	28-Lead Molded SOJ	Industrial
	CY7C199-20ZI	Z28	28-Lead Thin Small Outline Package	Military
	CY7C199-20DMB	D22	28-Lead (300Mil) CerDIP	
	CY7C199-20LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
	CY7C199L-20DMB	D22	28-Lead (300Mil) CerDIP	
	CY7C199L-20LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
25	CY7C199-25PC	P21	28-Lead (300Mil) Molded DIP	
	CY7C199-25SC	S21	28-Lead Molded SOIC	
	CY7C199-25VC	V21	28-Lead Molded SOJ	
	CY7C199-25ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199L-25ZI	Z28	28-Lead Thin Small Outline Package	Industrial
	CY7C199-25DMB	D22	28-Lead (300Mil) CerDIP	Military
	CY7C199-25LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
35	CY7C199-35PC	P21	28-Lead (300Mil) Molded DIP	Commercial
	CY7C199-35SC	S21	28-Lead Molded SOIC	
	CY7C199-35VC	V21	28-Lead Molded SOJ	
	CY7C199-35ZC	Z28	28-Lead Thin Small Outline Package	
	CY7C199-35DMB	D22	28-Lead (300Mil) CerDIP	Military
	CY7C199-35LMB	L54	28-Pin Rectangular Leadless Chip Carrier	
45	CY7C199-45DMB	D22	28-Lead (300Mil) CerDIP	Military
	CY7C199-45LMB	L54	28-Pin Rectangular Leadless Chip Carrier	

Shaded area contains preliminary information. Contact your Cypress sales representative for availability

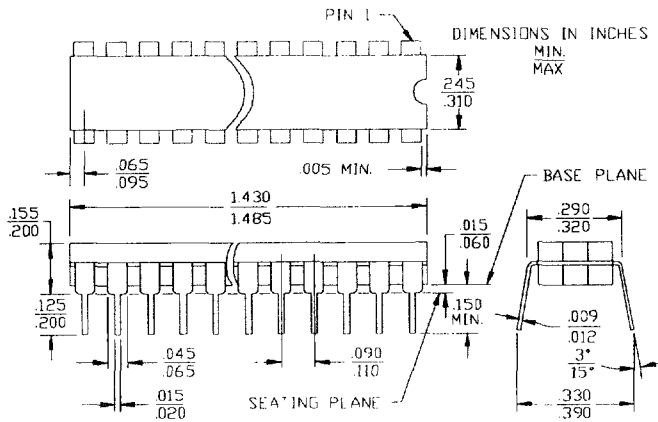
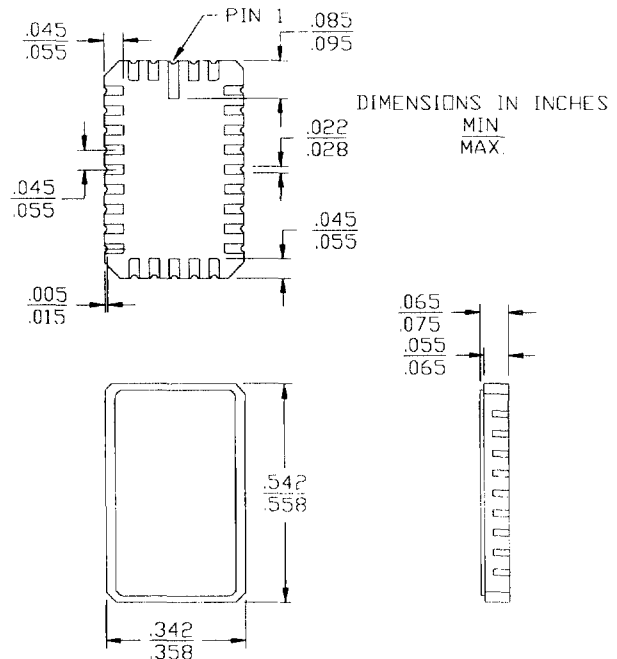
**MILITARY SPECIFICATIONS
Group A Subgroup Testing**
DC Characteristics

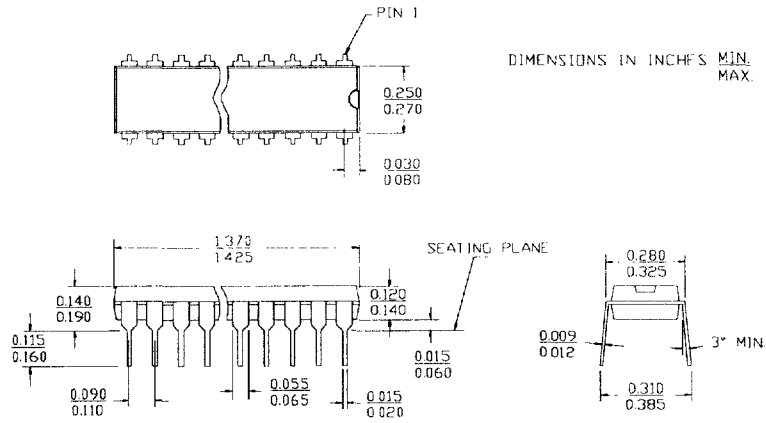
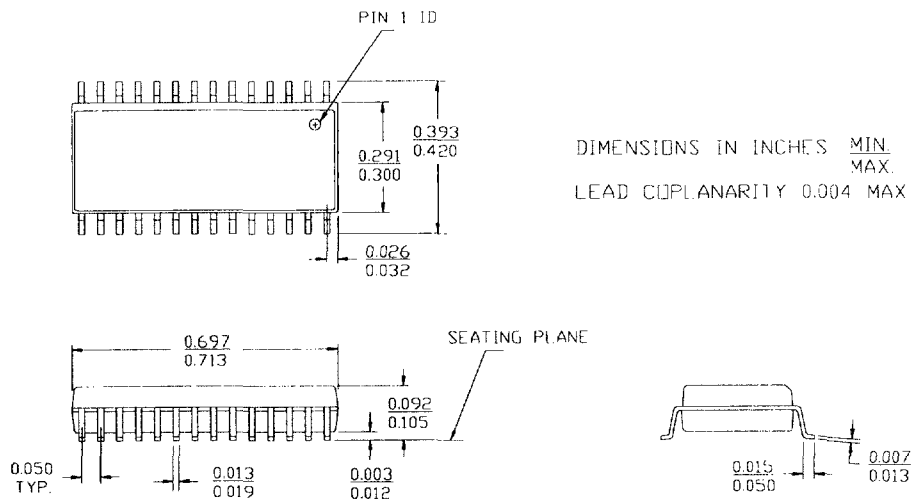
Parameter	Subgroups
V_{OH}	1, 2, 3
V_{OL}	1, 2, 3
V_{IH}	1, 2, 3
$V_{IL Max.}$	1, 2, 3
I_{IX}	1, 2, 3
I_{OZ}	1, 2, 3
I_{CC}	1, 2, 3
I_{SB1}	1, 2, 3
I_{SB2}	1, 2, 3

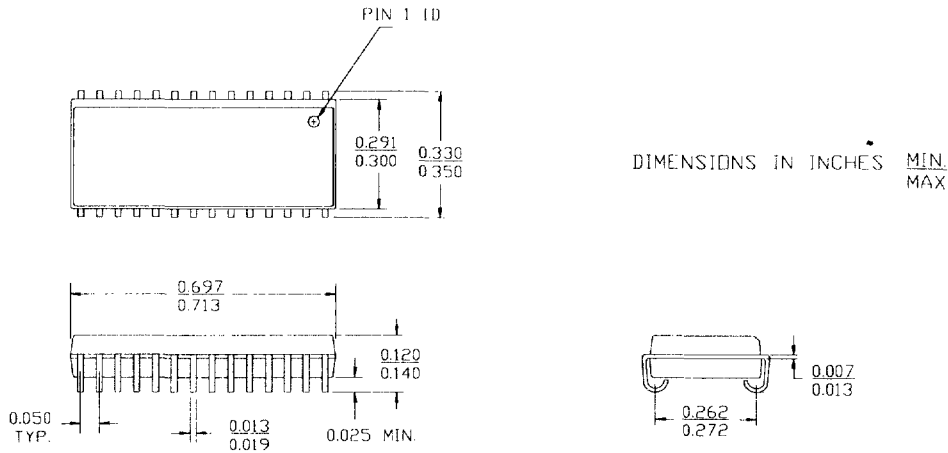
Switching Characteristics

Parameter	Subgroups
READ CYCLE	
t_{RC}	7, 8, 9, 10, 11
t_{AA}	7, 8, 9, 10, 11
t_{OHA}	7, 8, 9, 10, 11
t_{ACE}	7, 8, 9, 10, 11
t_{DOE}	7, 8, 9, 10, 11
WRITE CYCLE	
t_{WC}	7, 8, 9, 10, 11
t_{AA}	7, 8, 9, 10, 11
t_{AW}	7, 8, 9, 10, 11
t_{HA}	7, 8, 9, 10, 11
t_{SA}	7, 8, 9, 10, 11
t_{PWE}	7, 8, 9, 10, 11
t_{SD}	7, 8, 9, 10, 11
t_{HD}	7, 8, 9, 10, 11

Document #: 38-00239-D

Package Diagrams
28-Lead (300-Mil) CerDIP D22
MIL-STD-1835 D-15Config.A

28-Pin Rectangular Leadless Chip Carrier L54
MIL-STD-1835 C-11A


Package Diagrams (continued)
28-Lead (300-Mil) Molded DIP P21

28-Lead (300-Mil) Molded SOIC S21


Package Diagrams (continued)
28-Lead (300-Mil) Molded SOJV21

28-Lead Thin Small Outline Package Z28

DIMENSION IN MM (INCH)

